To all our customers

Regarding the change of names mentioned in the document, such as Mitsubishi Electric and Mitsubishi XX, to Renesas Technology Corp.

The semiconductor operations of Hitachi and Mitsubishi Electric were transferred to Renesas
Technology Corporation on April 1st 2003. These operations include microcomputer, logic, analog
and discrete devices, and memory chips other than DRAMs (flash memory, SRAMs etc.)
Accordingly, although Mitsubishi Electric, Mitsubishi Electric Corporation, Mitsubishi
Semiconductors, and other Mitsubishi brand names are mentioned in the document, these names
have in fact all been changed to Renesas Technology Corp. Thank you for your understanding.
Except for our corporate trademark, logo and corporate statement, no changes whatsoever have been
made to the contents of the document, and these changes do not constitute any alteration to the
contents of the document itself.

Note: Mitsubishi Electric will continue the business operations of high frequency & optical devices and power devices.

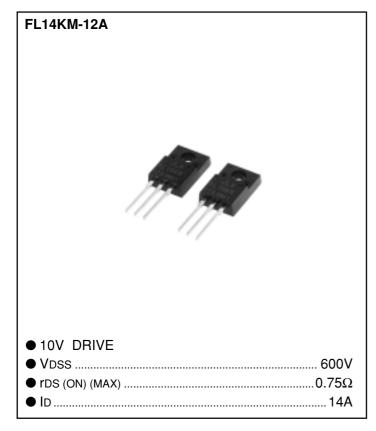
Renesas Technology Corp. Customer Support Dept. April 1, 2003

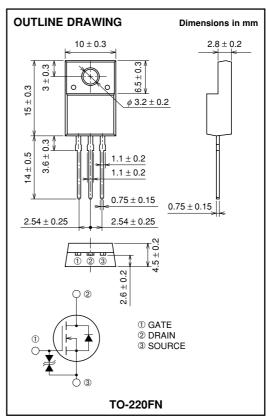


MITSUBISHI Nch POWER MOSFET

FL14KM-12A

HIGH-SPEED SWITCHING USE





APPLICATION

SMPS, Inverter type fluorescent light sets, etc.

MAXIMUM RATINGS (Tc = 25° C)

Symbol	Parameter	Conditions	Ratings	Unit
VDSS	Drain-source voltage	VGS = 0V	600	V
Vgss	Gate-source voltage	VDS = 0V	±30	V
ID	Drain current		14	Α
IDM	Drain current (Pulsed)		42	Α
IDA	Avalanche current (Pulsed)	L = 200μH	14	Α
PD	Maximum power dissipation		40	W
Tch	Channel temperature		− 55 ~ +150	°C
Tstg	Storage temperature		− 55 ~ +150	°C
Viso	Isolation voltage	AC for 1 minute, Terminal to case	2000	V
_	Weight	Typical value	2.0	g

MITSUBISHI Nch POWER MOSFET

FL14KM-12A

HIGH-SPEED SWITCHING USE

ELECTRICAL CHARACTERISTICS (Tch = 25°C)

Symbol	Parameter	Test conditions	Limits			Limit
			Min.	Тур.	Max.	Unit
V (BR) DSS	Drain-source breakdown voltage	ID = 1mA, VGS = 0V	600	_	_	V
V (BR) GSS	Gate-source breakdown voltage	$IG = \pm 100 \mu A$, $VDS = 0V$	±30	_	_	V
Igss	Gate-source leakage current	$VGS = \pm 25V$, $VDS = 0V$	_	_	±10	μΑ
IDSS	Drain-source leakage current	VDS = 600V, VGS = 0V	_	_	1	mA
VGS (th)	Gate-source threshold voltage	ID = 1mA, VDS = 10V	2.0	3.0	4.0	V
rDS (ON)	Drain-source on-state resistance	ID = 7A, VGS = 10V	_	0.58	0.75	Ω
VDS (ON)	Drain-source on-state voltage	ID = 7A, VGS = 10V	_	4.06	5.25	V
yfs	Forward transfer admittance	ID = 7A, VDS = 10V	_	11	_	S
Ciss	Input capacitance	VDS = 25V, VGS = 0V, f = 1MHz	_	1600	_	pF
Coss	Output capacitance		_	210	_	pF
Crss	Reverse transfer capacitance		_	80	_	pF
td (on)	Turn-on delay time	- VDD = 200V, ID = 7A, VGS = 10V, RGEN = RGS = 50Ω	_	30	_	ns
tr	Rise time		_	60	_	ns
td (off)	Turn-off delay time		_	290	_	ns
tf	Fall time		_	120	_	ns
VsD	Source-drain voltage	Is = 7A, Vgs = 0V	_	1.5	2.0	V
Rth (ch-c)	Thermal resistance	Channel to case	_	_	3.13	°C/W